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Aehr Test Systems

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**Aehr Test Systems to Exhibit at SPIE Photonics West 2017
in San Francisco**

Fremont, CA (January 30, 2017) - Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of test and burn-in equipment for semiconductors and integrated optical devices, today announced that it will be exhibiting at the SPIE Photonics West 2017 Conference January 31 – February 2 in San Francisco, CA at the Moscone Convention Center (Booth #6023).

The Company will be showcasing its solutions for both wafer level and module level burn-in and test of optical devices, including its FOX-XP next generation test and burn-in system for high volume production and early failure rate (EFR) test. SPIE is the world's largest event focusing on photonics technologies and showcases the latest innovations across a wide range of technologies.

"We continue to be very excited about the sensor and photonics markets, which we believe will be a significant market for Aehr Test, and look forward to our first time exhibiting at Photonics West" said Gayn Erickson, President and CEO of Aehr Test Systems. "As we've stated before, a key market driver for Aehr Test is the rapid automotive growth of integrated optical devices in sensors, Advanced Driver Assistance Systems (ADAS) and entertainment, which have substantially higher requirements for initial quality and long-term reliability. Other key growing markets for integrated optical devices are mobile devices, high-performance servers and data centers, where the use of optical devices for sensing and communications is increasing with every new product generation. We believe that these are extremely interesting fields that are going to drive an entirely new level of quality and reliability expectation of hardware systems and pose a very interesting long-term opportunity for the Company."

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and WaferPak contactors. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. For more information, please visit Aehr Test's website at www.aehr.com.

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